

AUIRFB8409-VB Datasheet

N-Channel 40-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	40				
$R_{DS(on)} (\Omega)$ at $V_{GS} = 10 V$	0.00084				
I _D (A)	409				
Configuration	Single				
Qg (nC)	250				

FEATURES

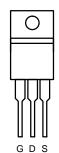
- TrenchFET[®] Power MOSFET
- 100 % R_g and UIS Tested

APPLICATIONS

- Synchronous Rectification
- Power Supplies

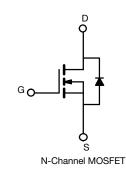


COMPLIANT HALOGEN



Top View

TO-220AB



PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-source voltage		V _{DS}	40	V	
Gate-source voltage		V _{GS}	± 20	7 V	
Continuous drain current ^a	T _C = 25 °C	1	409		
	T _C = 125 °C	- I _D	320		
Continuous source current (diode conduction) ^a		Is	409	A	
Pulsed drain current ^b		I _{DM}	600		
Single pulse avalanche current	L = 0.1 mH	I _{AS}	100		
Single pulse avalanche energy	L = 0.1 mH	E _{AS}	500	mJ	
Maximum power dissipation ^b	T _C = 25 °C	D	375	W	
	T _C = 125 °C	PD	125	vv	
Operating junction and storage temperature	e range	T _J , T _{stg}	-55 to +175	°C	

THERMAL RESISTANCE RATINGS				
PARAMETER		SYMBOL	LIMIT	UNIT
Junction-to-ambient	PCB mount ^c	R _{thJA}	40	°C/W
Junction-to-case (drain)		R _{thJC}	0.4	0/10

Notes

a. Based on T = 25 °C.

b. Pulse test; pulse width $\leq 300~\mu s,~duty~cycle \leq 2~\%$

c. When mounted on 1" square PCB (FR4 material)

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-source breakdown voltage	V _{DS}	V _{GS} =	= 0 V, I _D = 250 μΑ	40	-	-	v
Gate-source threshold voltage	V _{GS(th)}	V _{DS} =	- V _{GS} , I _D = 250 μΑ	2.5	3.0	3.5	v
Gate-source leakage	I _{GSS}	V _{DS} =	0 V, $V_{GS} = \pm 20$ V	-	-	± 100	nA
Zero gate voltage drain current	I _{DSS}	$V_{GS} = 0 V$ $V_{DS} = 40 V$		-	-	1	
		$V_{GS} = 0 V$	V _{DS} = 40 V, T _J = 125 °C	-	-	50	μA
		$V_{GS} = 0 V$	V _{DS} = 40 V, T _J = 175 °C	-	-	300	μA
On-state drain current ^a	I _{D(on)}	V _{GS} = 10 V	$V_{DS} \ge 5 V$	100	-	-	Α
		$V_{GS} = 10 V$	I _D = 35 A	-	0.00084	-	
Drain-source on-state resistance ^a	R _{DS(on)}	$V_{GS} = 10 V$	I _D = 35 A, T _J = 125 °C	-	0.00140	-	Ω
		$V_{GS} = 10 V$	I _D = 35 A, T _J = 175 °C	-	0.00164	-	
Forward transconductance b	9 _{fs}	$V_{DS} = 15 \text{ V}, \text{ I}_{D} = 30 \text{ A}$		-	196	-	S
Dynamic ^b							
Input capacitance	C _{iss}			-	11 938	15 525	
Output capacitance	C _{oss}	$V_{GS} = 0 V$	V _{DS} = 25 V, f = 1 MHz	-	11 163	14 520	pF
Reverse transfer capacitance	C _{rss}			-	282	370	
Total gate charge ^c	Qg			-	158	250	
Gate-source charge ^c	Q _{gs}	$V_{GS} = 10 V$	$V_{DS} = 20 \text{ V}, \text{ I}_{D} = 100 \text{ A}$	-	44	-	nC
Gate-drain charge ^c	Q _{gd}			-	22	-	
Gate resistance	R _g	f = 1 MHz		2.70	5.44	8.20	Ω
Turn-on delay time ^c	t _{d(on)}			-	16	25	
Rise time ^c	tr	$\label{eq:VDD} \begin{array}{l} V_{DD} = 20 \; V, \; R_{L} = 0.2 \; \Omega \\ I_{D} \cong 100 \; A, \; V_{GEN} = 10 \; V, \; R_{g} = 1 \; \Omega \end{array}$		-	10	17	- ns
Turn-off delay time ^c	t _{d(off)}			-	103	160	
Fall time ^c	t _f			-	61	95	
Source-Drain Diode Ratings and Chara	cteristics ^b						
Pulsed current ^a	I _{SM}			-	-	260	Α
Forward voltage	V_{SD}	$I_F = 60 \text{ A}, V_{GS} = 0 \text{ V}$		-	0.81	1.5	V
Body diode reverse recovery time	t _{rr}			-	165	350	ns
Body diode reverse recovery charge	Q _{rr}			-	530	1100	nC
Reverse recovery fall time	t _a	$I_F = 30$	A, di/dt = 100 A/µs	-	66	-	
Reverse recovery rise time	t _b]		-	99	-	ns
Body diode peak reverse recovery current	I _{RM(REC)}			-	-6.2	-	Α

Notes

a. Pulse test; pulse width $\leq 300~\mu s,~duty~cycle \leq 2~\%$

b. Guaranteed by design, not subject to production testing

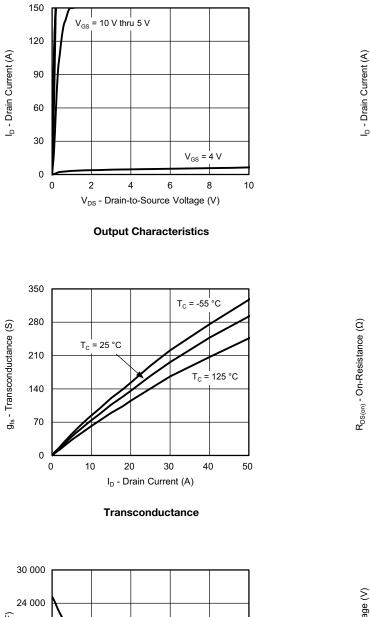
c. Independent of operating temperature

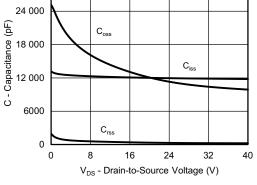
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

emi

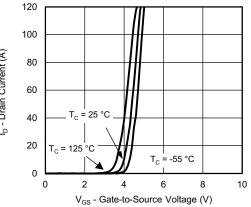


TYPICAL CHARACTERISTICS ($T_A = 25 \text{ °C}$, unless otherwise noted)

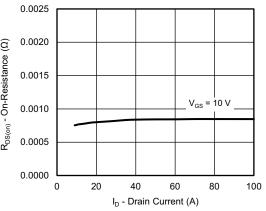




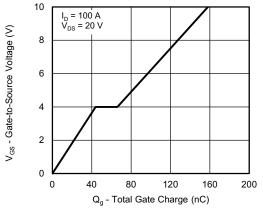
Capacitance



Transfer Characteristics



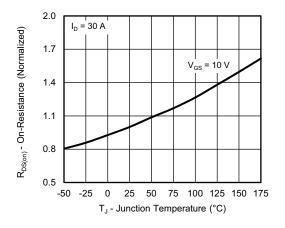
On-Resistance vs. Drain Current



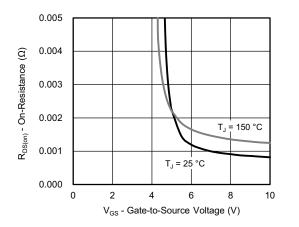
Gate Charge



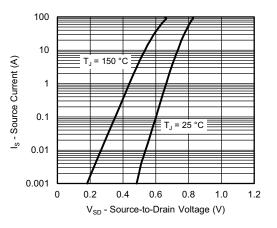
TYPICAL CHARACTERISTICS ($T_A = 25 \text{ °C}$, unless otherwise noted)



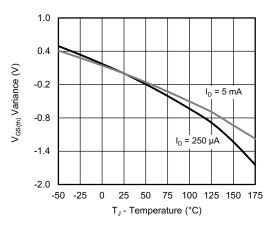
On-Resistance vs. Junction Temperature

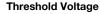


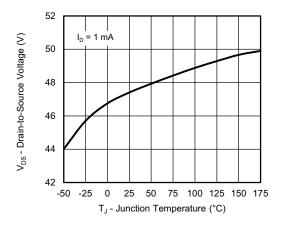
On-Resistance vs. Gate-to-Source Voltage



Source Drain Diode Forward Voltage



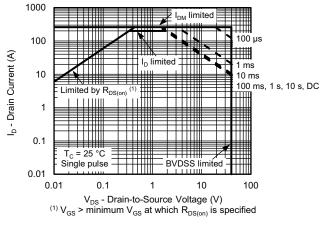




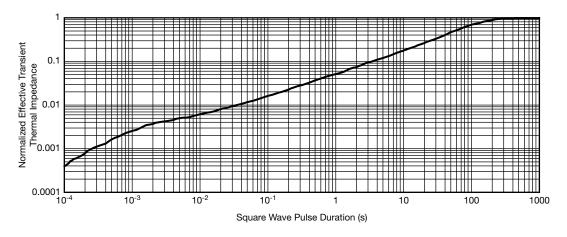
Drain Source Breakdown vs. Junction Temperature



THERMAL RATINGS ($T_A = 25 \ ^{\circ}C$, unless otherwise noted)



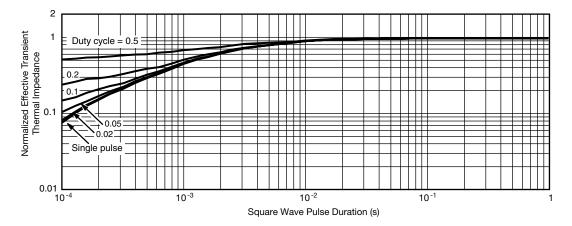
Safe Operating Area



Normalized Thermal Transient Impedance, Junction-to-Ambient



THERMAL RATINGS ($T_A = 25 \text{ °C}$, unless otherwise noted)



Normalized Thermal Transient Impedance, Junction-to-Case

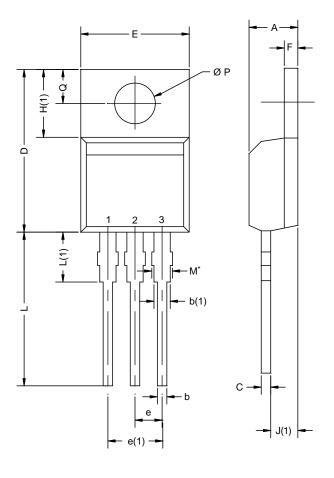
Note

- The characteristics shown in the two graphs
- Normalized Transient Thermal Impedance Junction-to-Ambient (25 °C)
- Normalized Transient Thermal Impedance Junction-to-Case (25 °C)

are given for general guidelines only to enable the user to get a "ball park" indication of part capabilities. The data are extracted from single pulse transient thermal impedance characteristics which are developed from empirical measurements. The latter is valid for the part mounted on printed circuit board - FR4, size 1" x 1" x 0.062", double sided with 2 oz. copper, 100 % on both sides. The part capabilities can widely vary depending on actual application parameters and operating conditions



TO-220AB



	MILLIN	IETERS	INCHES		
DIM.	MIN.	MAX.	MIN.	MAX.	
А	4.25	4.65	0.167	0.183	
b	0.69	1.01	0.027	0.040	
b(1)	1.20	1.73	0.047	0.068	
С	0.36	0.61	0.014	0.024	
D	14.85	15.49	0.585	0.610	
E	10.04	10.51	0.395	0.414	
е	2.41	2.67	0.095	0.105	
e(1)	4.88	5.28	0.192	0.208	
F	1.14	1.40	0.045	0.055	
H(1)	6.09	6.48	0.240	0.255	
J(1)	2.41	2.92	0.095	0.115	
L	13.35	14.02	0.526	0.552	
L(1)	3.32	3.82	0.131	0.150	
ØР	3.54	3.94	0.139	0.155	
Q	2.60	3.00	0.102	0.118	

Notes

* M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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